

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/657,394	MERTZ ET AL.	
Examiner	Art Unit	
Christopher M. Keehan	1712	

SEARCHED					
Class	Subclass	Date	Examiner		
428	447	7/5/2005	СМК		
	219				
528	31				
522	53				
	31				
	48				
	170				
		-			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	7/5/2005	СМК	